

74ALVC374

Octal D-type flip-flop; positive-edge trigger; 3-state

Rev. 02 — 17 October 2007

Product data sheet

1. General description

The 74ALVC374 is an octal D-type flip-flop featuring separate D-type inputs for each flip-flop and 3-state outputs for bus-oriented applications. A clock input (CP) and an outputs enable input (\overline{OE}) are common to all flip-flops.

The eight flip-flops will store the state of their individual D-inputs that meet the set-up and hold times requirements on the LOW to HIGH CP transition.

When pin \overline{OE} is LOW, the contents of the eight flip-flops is available at the outputs. When pin \overline{OE} is HIGH, the outputs go to the high-impedance OFF-state. Operation of the \overline{OE} input does not affect the state of the flip-flops.

The 74ALVC374 is functionally identical to the 74ALVC574, but has a different pin arrangement.

2. Features

- Wide supply voltage range from 1.65 V to 3.6 V
- 3.6 V tolerant inputs/outputs
- CMOS low power consumption
- Direct interface with TTL levels (2.7 V to 3.6 V)
- Power-down mode
- Latch-up performance exceeds 250 mA
- Complies with JEDEC standards:
 - ◆ JESD8-7 (1.65 V to 1.95 V)
 - ◆ JESD8-5 (2.3 V to 2.7 V)
 - ◆ JESD8B/JESD36 (2.7 V to 3.6 V)
- ESD protection:
 - ◆ HBM JESD22-A114E exceeds 2000 V
 - ◆ MM JESD22-A 115-A exceeds 200 V

3. Ordering information

Table 1. Ordering information

Type number	Package			Version
	Temperature range	Name	Description	
74ALVC374D	-40 °C to +85 °C	SO20	plastic small outline package; 20 leads; body width 7.5 mm	SOT163-1
74ALVC374PW	-40 °C to +85 °C	TSSOP20	plastic thin shrink small outline package; 20 leads; body width 4.4 mm	SOT360-1
74ALVC374BQ	-40 °C to +85 °C	DHVQFN20	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 20 terminals; body 2.5 × 4.5 × 0.85 mm	SOT764-1

4. Functional diagram

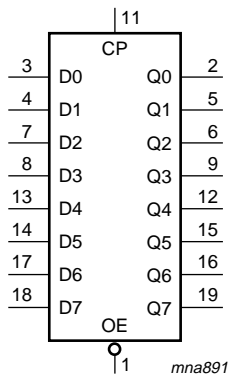


Fig 1. Logic symbol

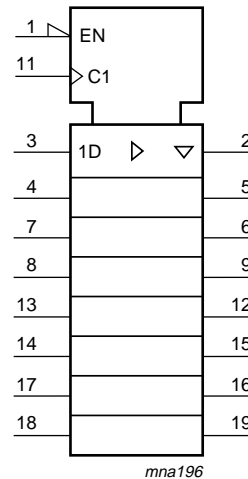


Fig 2. IEC logic symbol

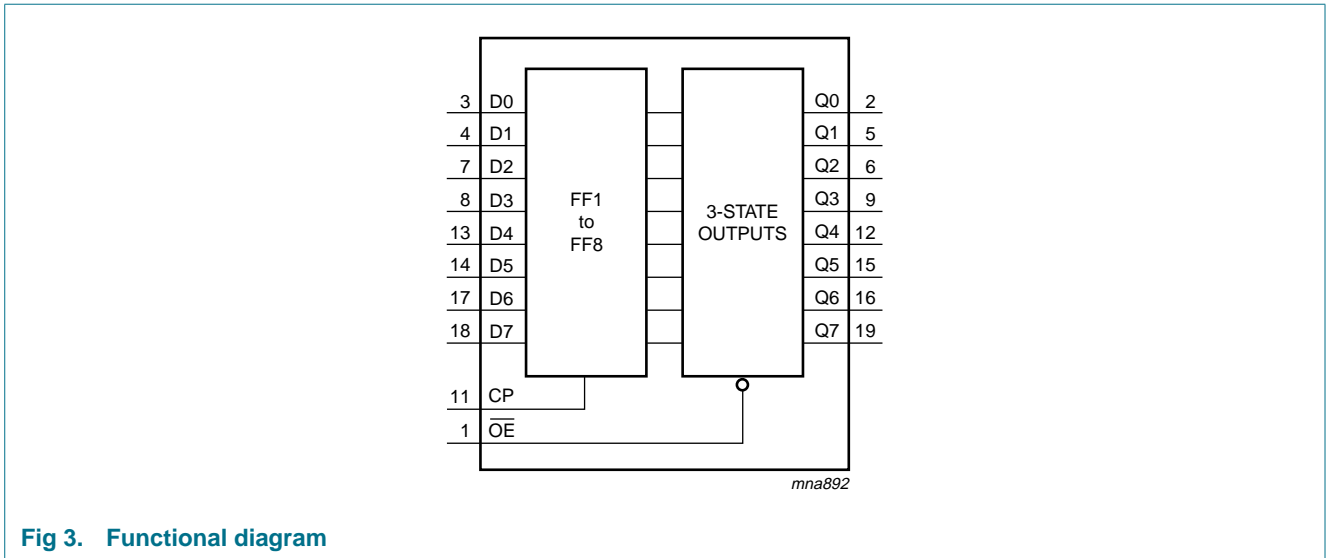


Fig 3. Functional diagram

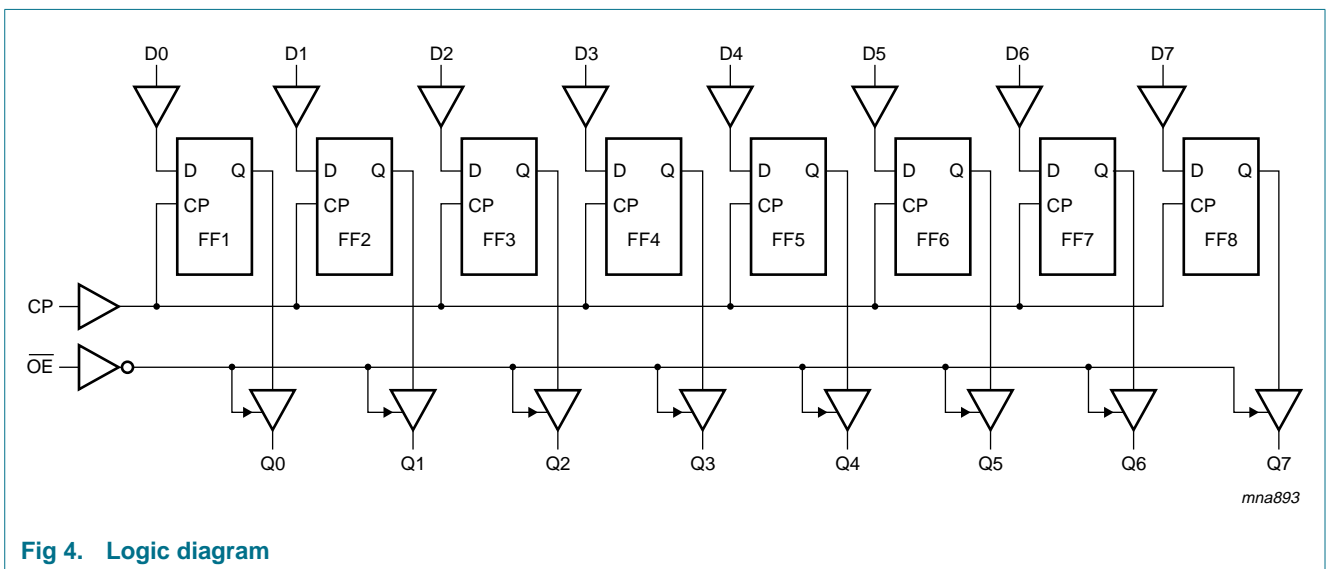


Fig 4. Logic diagram

5. Pinning information

5.1 Pinning

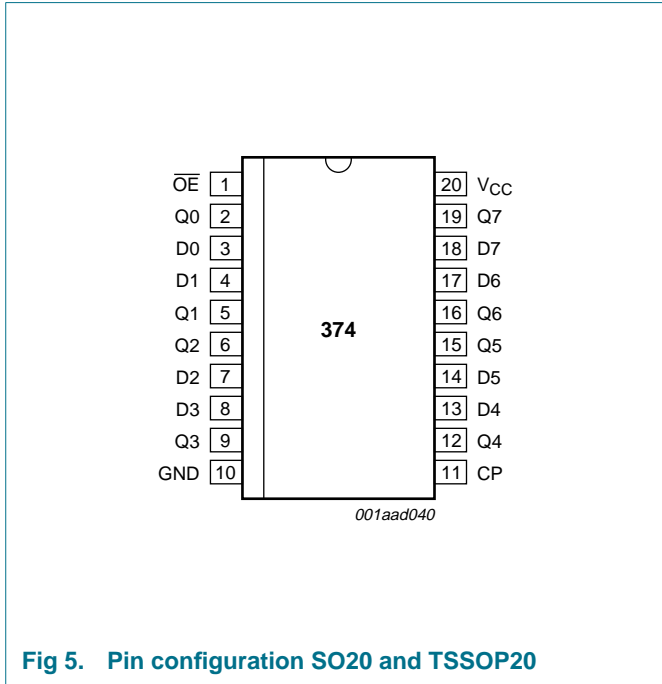


Fig 5. Pin configuration SO20 and TSSOP20

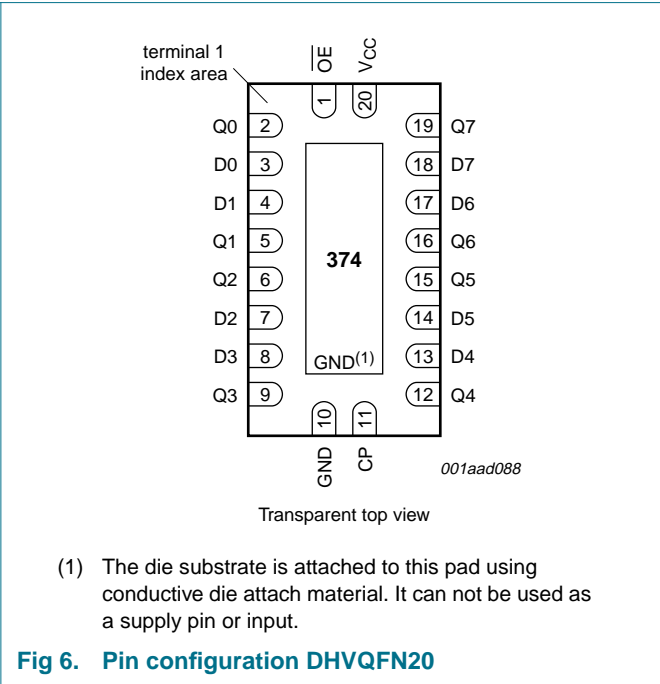


Fig 6. Pin configuration DHVQFN20

5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
D[0:7]	3, 4, 7, 8, 13, 14, 17, 18	data input
CP	11	clock input (LOW to HIGH, edge-triggered)
OE	1	output enable input (active LOW)
Q[0:7]	2, 5, 6, 9, 12, 15, 16, 19	3-state flip-flop output
VCC	20	supply voltage
GND	10	ground (0 V)

6. Functional description

Table 3. Function table^[1]

Operating mode	Input			Internal flip-flop	Output Qn
	OE	CP	Dn		
Load and read register	L	↑	l	L	L
	L	↑	h	H	H
Load register and disable outputs	H	↑	l	L	Z
	H	↑	h	H	Z

- [1] H = HIGH voltage level
 h = HIGH voltage level one set-up time prior to the LOW to HIGH CP transition
 L = LOW voltage level
 l = LOW voltage level one set-up time prior to the LOW to HIGH CP transition
 Z = high-impedance OFF-state
 ↑ = LOW to HIGH clock transition

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+4.6	V
I_{IK}	input clamping current	$V_I < 0$ V	-50	-	mA
V_I	input voltage		-0.5	+4.6	V
I_{OK}	output clamping current	$V_O > V_{CC}$ or $V_O < 0$ V	-	±50	mA
V_O	output voltage	output HIGH or LOW state	^[1] ^[2] -0.5	$V_{CC} + 0.5$	V
		output 3-state	-0.5	+4.6	V
		power-down mode, $V_{CC} = 0$ V	^[2] -0.5	+4.6	V
I_O	output current	$V_O = 0$ V to V_{CC}	-	±50	mA
I_{CC}	supply current		-	100	mA
I_{GND}	ground current		-100	-	mA
T_{stg}	storage temperature		-65	+150	°C
P_{tot}	total power dissipation	$T_{amb} = -40$ °C to +85 °C	^[3] -	500	mW

- [1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 [2] When $V_{CC} = 0$ V (power-down mode), the output voltage can be 3.6 V in normal operation.
 [3] For SO20 packages: above 70 °C derate linearly with 8 mW/K.
 For TSSOP20 packages: above 60 °C derate linearly with 5.5 mW/K.
 For DHVQFN20 packages: above 60 °C derate linearly with 4.5 mW/K.

8. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		1.65	3.6	V
V _I	input voltage		0	3.6	V
V _O	output voltage	output HIGH or LOW state	0	V _{CC}	V
		output 3-state	0	3.6	V
		power-down mode; V _{CC} = 0 V	0	3.6	V
T _{amb}	ambient temperature	in free air	-40	+85	°C
Δt/ΔV	input transition rise and fall rate	V _{CC} = 1.65 V to 2.7 V	-	20	ns/V
		V _{CC} = 2.7 V to 3.6 V	-	10	ns/V

9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C			Unit
			Min	Typ ^[1]	Max	
V _{IH}	HIGH-level input voltage	V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}	-	-	V
		V _{CC} = 2.3 V to 2.7 V	1.7	-	-	V
		V _{CC} = 2.7 V to 3.6 V	2.0	-	-	V
V _{IL}	LOW-level input voltage	V _{CC} = 1.65 V to 1.95 V	-	-	0.35 × V _{CC}	V
		V _{CC} = 2.3 V to 2.7 V	-	-	0.7	V
		V _{CC} = 2.7 V to 3.6 V	-	-	0.8	V
V _{OH}	HIGH-level output voltage	V _I = V _{IH} or V _{IL}				
		I _O = -100 μA; V _{CC} = 1.65 V to 3.6 V	V _{CC} - 0.2	-	-	V
		I _O = -6 mA; V _{CC} = 1.65 V	1.25	1.51	-	V
		I _O = -12 mA; V _{CC} = 2.3 V	1.8	2.10	-	V
		I _O = -18 mA; V _{CC} = 2.3 V	1.7	2.01	-	V
		I _O = -12 mA; V _{CC} = 2.7 V	2.2	2.53	-	V
		I _O = -18 mA; V _{CC} = 3.0 V	2.4	2.76	-	V
V _{OL}	LOW-level output voltage	V _I = V _{IH} or V _{IL}				
		I _O = 100 μA; V _{CC} = 1.65 V to 3.6 V	-	-	0.2	V
		I _O = 6 mA; V _{CC} = 1.65 V	-	0.11	0.3	V
		I _O = 12 mA; V _{CC} = 2.3 V	-	0.17	0.4	V
		I _O = 18 mA; V _{CC} = 2.3 V	-	0.25	0.6	V
		I _O = 12 mA; V _{CC} = 2.7 V	-	0.16	0.4	V
		I _O = 18 mA; V _{CC} = 3.0 V	-	0.23	0.4	V
I _I	input leakage current	V _{CC} = 3.6 V; V _I = 3.6 V or GND	-	±0.1	±5	μA

Table 6. Static characteristics ...continued

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C			Unit
			Min	Typ ^[1]	Max	
I _{OZ}	OFF-state output current	V _I = V _{IH} or V _{IL} ; V _{CC} = 1.65 V to 3.6 V; V _O = 3.6 V or GND;	-	±0.1	±10	µA
I _{OFF}	power-off leakage supply	V _{CC} = 0 V; V _I or V _O = 0 V to 3.6 V	-	±0.1	±10	µA
I _{CC}	supply current	V _{CC} = 3.6 V; V _I = V _{CC} or GND; I _O = 0 A	-	0.2	10	µA
ΔI _{CC}	additional supply current	per input pin; V _{CC} = 3.0 V to 3.6 V; V _I = V _{CC} - 0.6 V; I _O = 0 A	-	5	750	µA
C _I	input capacitance		-	3.5	-	pF

[1] All typical values are measured at V_{CC} = 3.3 V (unless stated otherwise) and T_{amb} = 25 °C.

10. Dynamic characteristics

Table 7. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V). For test circuit see [Figure 10](#).

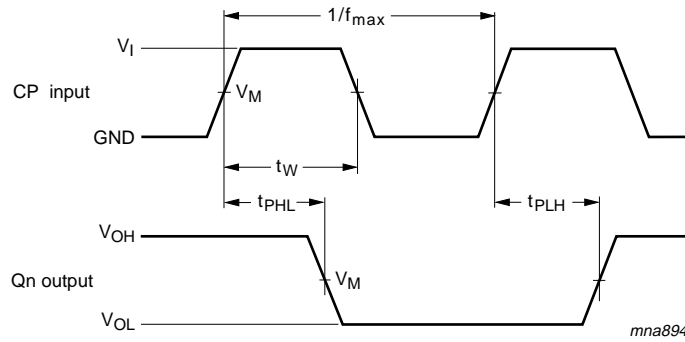
Symbol	Parameter	Conditions	-40 °C to +85 °C			Unit
			Min	Typ ^[1]	Max	
t _{pd}	propagation delay	CP to Qn; see Figure 7 ^[2]				
		V _{CC} = 1.65 V to 1.95 V	1.0	3.1	6.4	ns
		V _{CC} = 2.3 V to 2.7 V	1.0	2.3	3.9	ns
		V _{CC} = 2.7 V	1.0	2.5	3.6	ns
t _{en}	enable time	V _{CC} = 3.0 V to 3.6 V	1.0	2.5	3.6	ns
		\overline{OE} to Qn; see Figure 8 ^[2]				
		V _{CC} = 1.65 V to 1.95 V	1.0	3.2	6.4	ns
		V _{CC} = 2.3 V to 2.7 V	1.0	2.6	4.5	ns
t _{dis}	disable time	V _{CC} = 2.7 V	1.0	3.2	4.6	ns
		V _{CC} = 3.0 V to 3.6 V	1.0	2.4	4.0	ns
		\overline{OE} to Qn; see Figure 8 ^[2]				
		V _{CC} = 1.65 V to 1.95 V	1.5	3.6	7.0	ns
t _w	pulse width	V _{CC} = 2.3 V to 2.7 V	1.0	2.3	4.4	ns
		V _{CC} = 2.7 V	1.5	2.9	4.4	ns
		V _{CC} = 3.0 V to 3.6 V	1.0	2.8	4.4	ns
		clock HIGH or LOW; see Figure 7				
t _w	pulse width	V _{CC} = 1.65 V to 1.95 V	3.8	1.1	-	ns
		V _{CC} = 2.3 V to 2.7 V	3.3	0.9	-	ns
		V _{CC} = 2.7 V	3.3	0.8	-	ns
		V _{CC} = 3.0 V to 3.6 V	3.3	1.2	-	ns

Table 7. Dynamic characteristics ...continued
 Voltages are referenced to GND (ground = 0 V). For test circuit see [Figure 10](#).

Symbol	Parameter	Conditions	-40 °C to +85 °C			Unit
			Min	Typ ^[1]	Max	
t _{su}	set-up time	Dn to CP; see Figure 9				
		V _{CC} = 1.65 V to 1.95 V	0.8	-0.1	-	ns
		V _{CC} = 2.3 V to 2.7 V	0.8	0.1	-	ns
		V _{CC} = 2.7 V	0.8	0.3	-	ns
t _h	hold time	Dn to CP; see Figure 9				
		V _{CC} = 1.65 V to 1.95 V	0.8	-0.1	-	ns
		V _{CC} = 2.3 V to 2.7 V	0.8	0.1	-	ns
		V _{CC} = 2.7 V	0.8	0.4	-	ns
f _{max}	maximum frequency	see Figure 7				
		V _{CC} = 2.3 V to 2.7 V	100	200	-	MHz
		V _{CC} = 2.7 V	100	200	-	MHz
		V _{CC} = 3.0 V to 3.6 V	150	300	-	MHz
C _{PD}	power dissipation capacitance	per flip-flop; V _I = GND to V _{CC} ; V _{CC} = 3.3 V ^[3]				
		outputs HIGH or LOW state	-	21	-	pF
		outputs 3-state	-	13	-	pF

- [1] Typical values are measured at T_{amb} = 25 °C
- [2] t_{pd} is the same as t_{PHL} and t_{PLH}.
 t_{en} is the same as t_{PZH} and t_{PZL}.
 t_{dis} is the same as t_{PHZ} and t_{PLZ}.
- [3] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).
 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o)$ where:
 f_i = input frequency in MHz; f_o = output frequency in MHz
 C_L = output load capacitance in pF
 V_{CC} = supply voltage in Volts
 N = number of inputs switching
 $\Sigma(C_L \times V_{CC}^2 \times f_o)$ = sum of the outputs

11. Waveforms



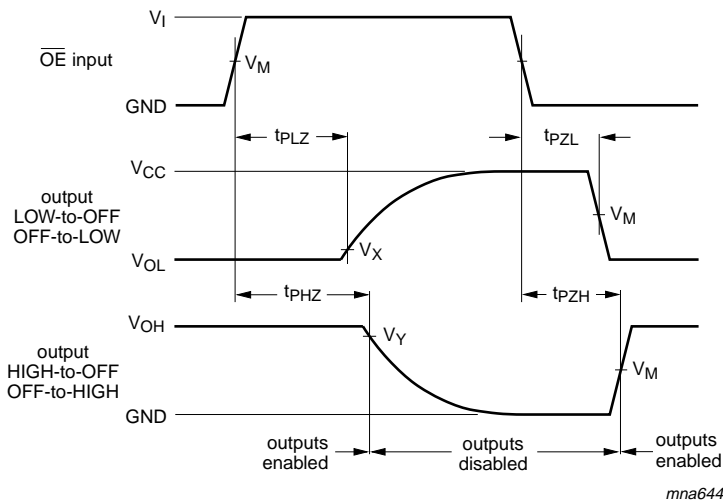
Measurement points are given in [Table 8](#).

V_{OL} and V_{OH} are the typical output voltage levels that occur with the output load.

Fig 7. Clock (CP) to output (Qn) propagation delays, the clock pulse width and the maximum frequency

Table 8. Measurement points

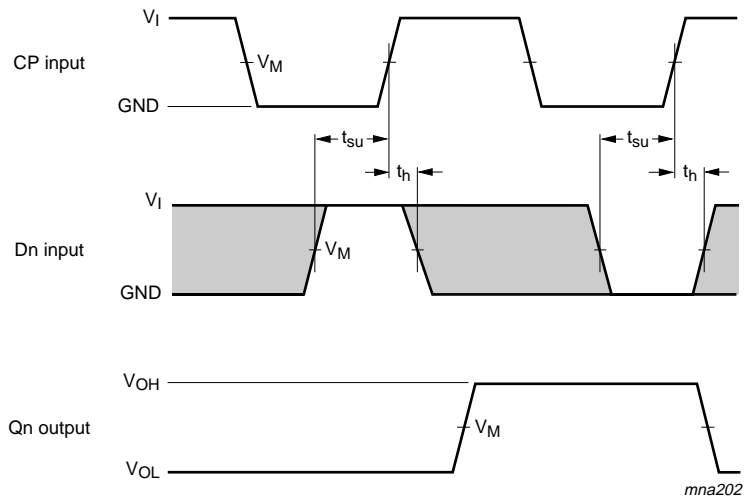
Supply voltage	Input	Output		
V_{CC}	V_M	V_M	V_x	V_y
1.65 V to 1.95 V	$0.5V_{CC}$	$0.5V_{CC}$	$V_{OL} + 0.15 V$	$V_{OH} - 0.15 V$
2.3 V to 2.7 V	$0.5V_{CC}$	$0.5V_{CC}$	$V_{OL} + 0.15 V$	$V_{OH} - 0.15 V$
2.7 V	2.7 V	1.5 V	$V_{OL} + 0.3 V$	$V_{OH} - 0.3 V$
3.0 V to 3.6 V	2.7 V	1.5 V	$V_{OL} + 0.3 V$	$V_{OH} - 0.3 V$



Measurement points are given in [Table 8](#).

V_{OL} and V_{OH} are the typical output voltage drops that occur with the output load.

Fig 8. Enable and disable times

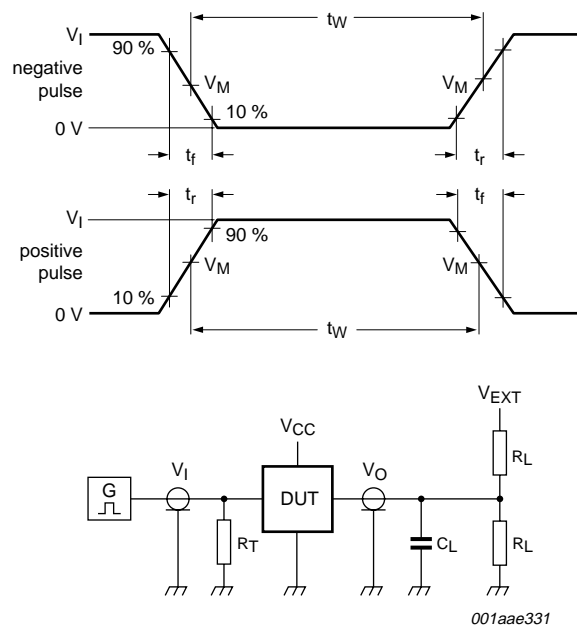


Measurement points are given in [Table 8](#).

V_{OL} and V_{OH} are the typical output voltage drops that occur with the output load.

The shaded areas indicate when the input is permitted to change for predicable output performance.

Fig 9. Data set-up and hold times for the Dn input to the CP input



Test data is given in [Table 9](#).

Definitions for test circuit:

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

R_T = Termination resistance should be equal to output impedance Z_o of the pulse generator.

V_{EXT} = External voltage for measuring switching times.

Fig 10. Test circuitry for switching times

Table 9. Test data

Supply voltage	Input		Load		V_{EXT}		
	V_I	t_r, t_f	C_L	R_L	t_{PLH}, t_{PHL}	t_{PLZ}, t_{PZL}	t_{PHZ}, t_{PZH}
1.65 V to 1.95 V	V_{CC}	≤ 2.0 ns	30 pF	1 k Ω	open	$2V_{CC}$	GND
2.3 V to 2.7 V	V_{CC}	≤ 2.0 ns	30 pF	500 Ω	open	$2V_{CC}$	GND
2.7 V	2.7 V	≤ 2.5 ns	50 pF	500 Ω	open	6 V	GND
3.0 V to 3.6 V	2.7 V	≤ 2.5 ns	50 pF	500 Ω	open	6 V	GND

12. Package outline

SO20: plastic small outline package; 20 leads; body width 7.5 mm

SOT163-1

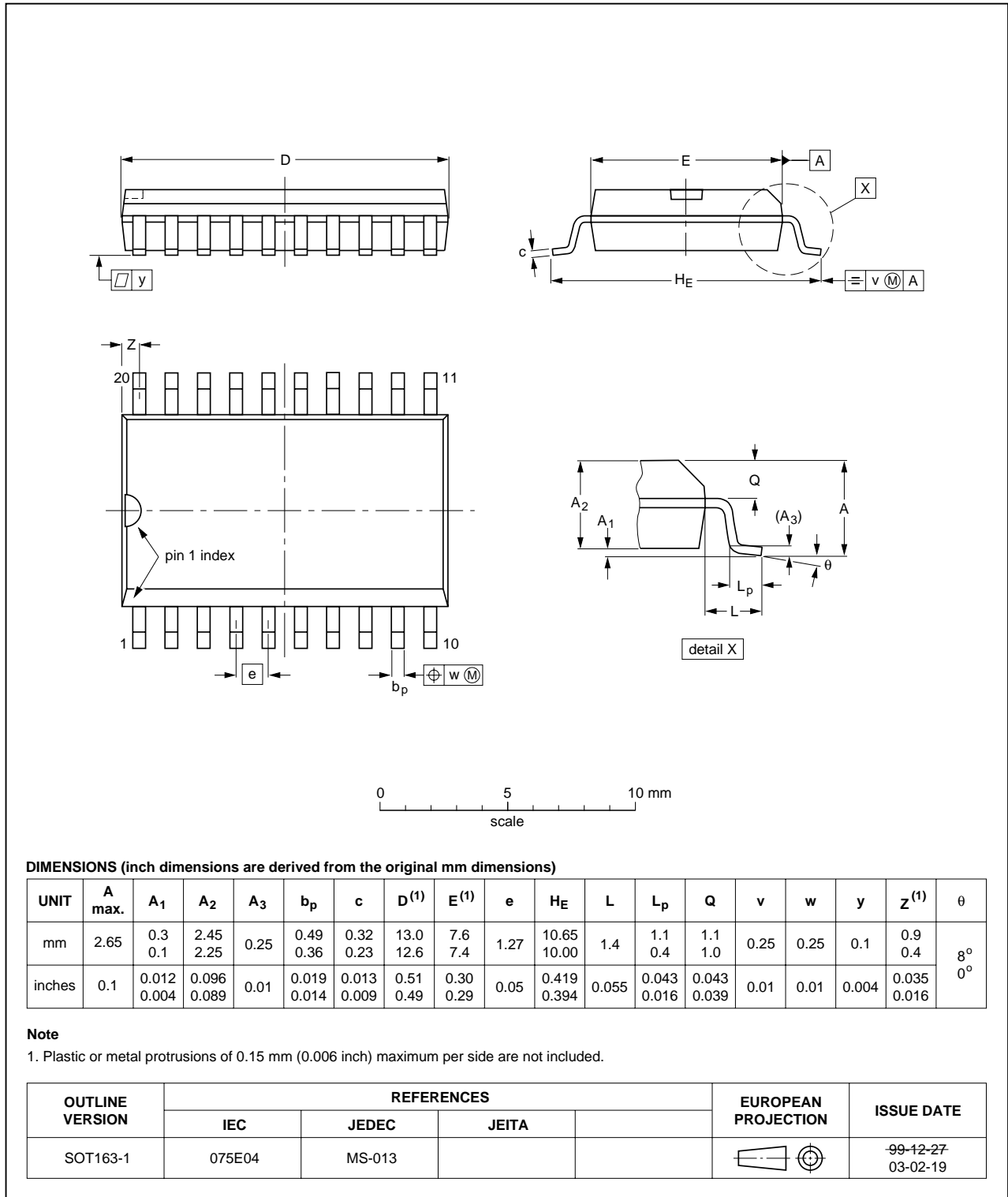


Fig 11. Package outline SOT163-1 (SO20)

TSSOP20: plastic thin shrink small outline package; 20 leads; body width 4.4 mm

SOT360-1

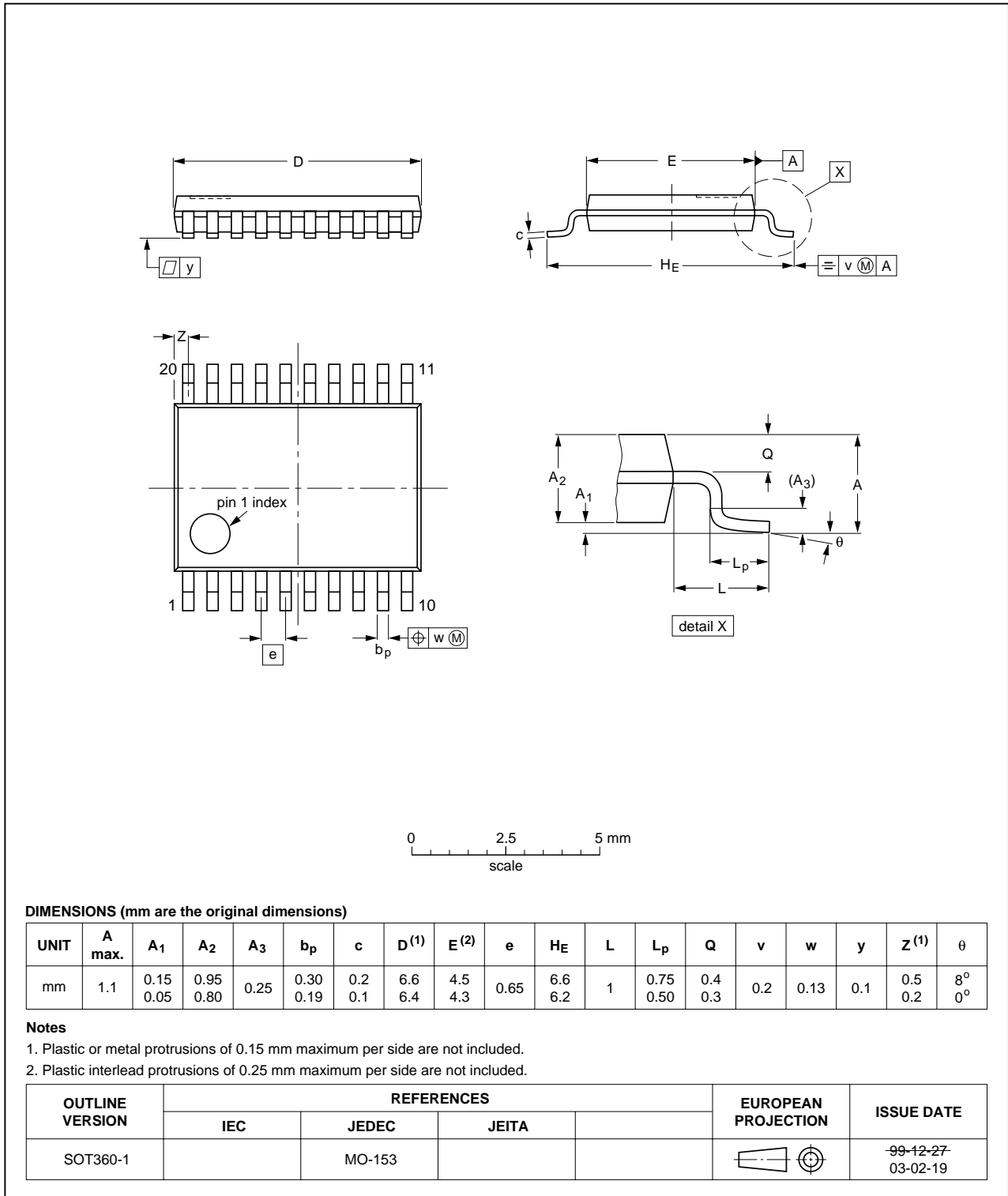


Fig 12. Package outline SOT360-1 (TSSOP20)

DHVQFN20: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 20 terminals; body 2.5 x 4.5 x 0.85 mm

SOT764-1

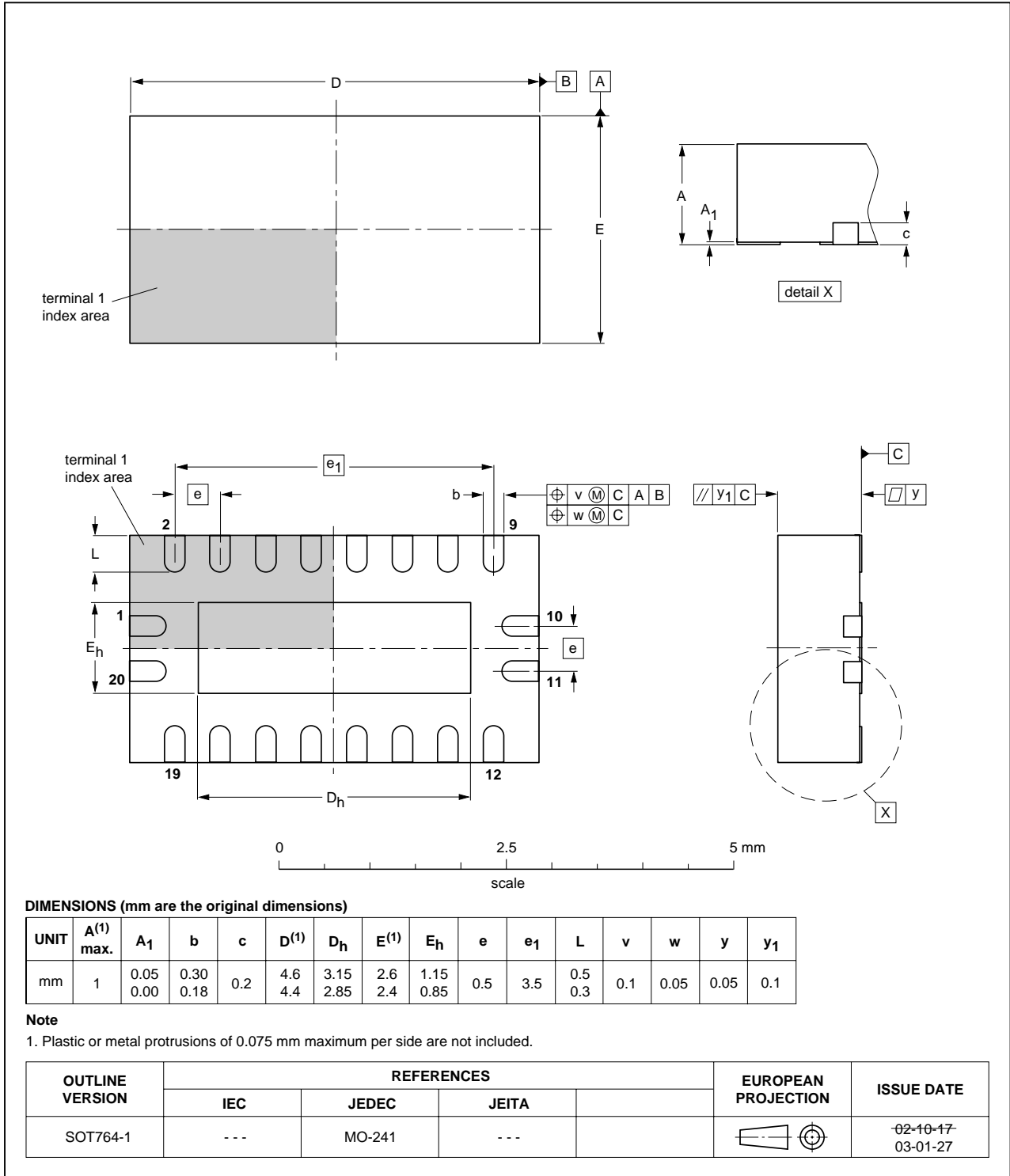


Fig 13. Package outline SOT764-1 (DHVQFN20)

13. Abbreviations

Table 10. Abbreviations

Acronym	Description
CDM	Charged Device Model
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

14. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ALVC374_2	20071017	Product data sheet	-	74ALVC374_1
Modifications:	<ul style="list-style-type: none"> • The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. • Legal texts have been adapted to the new company name where appropriate. • Section 3: DHVQFN20 package added. • Section 7: derating values added for DHVQFN20 package. • Section 12: outline drawing added for DHVQFN20 package. 			
74ALVC374_1	20020227	Product specification	-	-

15. Legal information

15.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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Date of release: 17 October 2007
 Document identifier: 74ALVC374_2